Form PTO-1449		Ų	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MIZZ-1534			SERIAL NO. 09/881,408		
		LIST OF ART CITED (Use several sheats		ıτ	APPLICANT: Kie Y. Ahn et al.						
					FILING DATE GROUP June 13, 2001 2814						
U.S. PATENT DOCUMENTS											
Euriner's Initials		Document Number	Crate	Name	Class	Substass Filing C		esenqon			
TL	*	6,664,186	12/2003	Callegari et al.							
	AB										
	AC										
	Q										
	Æ										
	4										
	AC.										
	2										
FOREIGN F	ATEN	DOCUMENTS									
		Document Number	Oxto	Country		Ctasa	Subclas	SS Tres	No No		
	W										
	*										
	AL										
OTHER RE	FEREN	ICES (including Author,	Title, Date, Pe	rtinent Pages, Etc.)							
	w										
	AN										
	49										
EXAMINER	I	DATE CONSIDE	RED	12/06/0	5			· · · · · ·			
EXAMINER: considered. I	initizi il nclude c	reference considered, whencopy of this form with next or	ther or not citatic ommunication to	on is in conformance with MP applicant.	EP 609; Draw line t	hrough cita	ation if no	t in conforman	ce and not		

Form PTO-	Form PTO-1449			U.S.	U.S. DEPARTMENT OF COMMERCE ATTY. DOCKET I MIZZ-1534		NO.	SER 09/81	IAL NO. 81,408		
		L	IST OF ART CITED	BY APPLICA	NT	APPLICANT Kie Y. Ahn, et al					
			PILE		FILING DATE June 13, 2001				UP		
			OCT 2 9 2002	12	U.S. PATENT DOCUMENTS			2814			
*Examinar Initial		D Na	Special Control of the Control of th	J	Name		Clus	Subclass	Filing Date If Appropriate		
P	AA	200	12/01 06536	08/2002	Loo et al						
π	AB	200	71/0024868	09/2001	Nagel et al						
TL.	AC	200	2/0006708	01/2002	Kang et al						
	AD							ECH			
	AE							ECH 40L0GY	RE		
	AF						36.5.14	790	CE 3		
	AG							CEN	VE 20		
	AH							ER.	2002 2002		
	Al						. 41	7800			
	AJ.				-		.1.				
	AK										
	ΑL										
		_			OREIGN PATENT DOCUMENT	5					
		Doc: Num	pment pment	Date	Country		Class	Subclass	Translation Yes No		
	AM	┢									
	AN	\vdash						_			
	AO AP-										
	AQ										
			нто	ER REFERENC	ES (including Author, Title, Date,	Pertinent Pages, Etc.)					
	AR							 -			
	AS										
	Ī										
	ΑŢ										
EXAMINER		_	+=		DATE CONSIDERE	12/	28/0	05			
*EXAMINER:	Initial i clude cop	f referen	ice considered, whether	r or not citation nunication to ap	is in conformance with MPEP 6 plicant.			not in confer	mance and not		

Form PTO-1	449		U.S. I	DEPARTMENT OF COMMERCE INT AND TRADEMARK OFFICE	ATTY, DOCKET N MIZZ-1534	€ O.	SER.	IAL NO.	
		LIST OF ADVICIOND		NT	APPLICANT Rie Y. Ahn, at al				
			2000		FILING DATE June 13, 2001		GR0 2814		
		00.1.		U.S. PATENT DOCUMENTS					نز
*Examiner Initial		Document Number	CARRE	Name		Class	Subclass	Filing Da If Appropri	iete
72	A	6.387,761	08/2002	Shib	27	44.	EUN	-	विव
72	АВ	4,432,035	02/1984	Hisloh es al		ř			ice
P	AC	6,436,777	08/2002	Ota			j	10. 00	TA TA
72	AD	6,172,385	01/2001	Duncombe et al			1	里夏	<u></u> 'a
P	AE	5,566,045	10/1996	Summerfelt et al			i i	1 2002 Y CENTER 2800	•
R	AF	5,554,564	09/1996	Nishioka et al				Š	
R	AG	5,605,858	02/1997	Nishioka et ej			₩.		
TZ	AH	6,407,422	06/2002	Asano et al					
	Ai								
	AJ							• •	
	AK								
1	AL								
	ı			OREIGN PATENT DOCUMENT	s				
		Document Number	Date	Country		Class	Subclass	Translatio	No No
	AM								
	AN AO								
	AP								
	AQ								\neg
		ОТН	ER REFERENC	ES (including Author, Title, Date,	Pertinent Pages, Etc.)				
	AR								
		·							
	AS								
									\dashv
	٨Τ								\dashv
EXAMINER	-	4=		DATE CONSIDERE	° 12	2/2.	8/01	-	\neg
*EXAMINER; considered, to	Initial is	reference considered, whether	r or not citation nunisation to ap	is in conformance with MPEP 6				mence and not	\neg

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE						ATTY, DOCKET NO. SERIAL NO. MI22-1534					
	ST (OF ART CITE	PLICANT	Z	APPLICANT Kie Y. Ahn el	: a1					
-	51 ((Use several sheets		SEP 0 4 2001	Cros	FILING DATE			GROU	JP.	
U.S. PATE	NT D	OCUMENTS	12	Į,							
Examiner's Initials		Document Number	Date	Name MADENARY	57		Class	Sub	lass	Filing Da	ite oriate
7	AA	6,020,024	2-1-2000	Maiti et si.							
	AB						•				
	AC										
	AD										
	AE								······································		
	AF										
	AG										
	АН										
	AI										
	AJ								-		
	AK										
	AL						·				
FOREIGN	PATE	NT DOCUMENT	S				<u>I</u>			<u> </u>	
		Document Number	Date	Country			Class	Şubo	lass	Translat Yes	on No
	АМ										
	AN	-									
	AO										
	AP										
	AQ										
OTHER RE	FER	ENCES (includin	g Author, T	itle, Date, Pertinen	t P	ages, Etc.)	<u>l</u>			1,	
	AR		-								
-	AS				,,,,,,,,,						
	AT										
EXAMINER			·	•		NSIDERED					
				20	• i	Fub. 200 Z	•				
EXAMINER: conformance	Initial and no	if reference consider t considered. Include	red, whether o	or not citation is in con form with next communic	forn atio	nance with MP on to applicant.	EP 609; Dr	aw line	throug	h citation	if not in

Appropriate Constitution of the Constitution o			U.S. DEPARTMENT OF COMMERCE ATTY, DOCKE			ю.	SER	SERIAL NO. 09/881,408		
	ç	LIST OF ART CITED	BY APPLICAN	ENT AND TRADEMARK OFFICE NT	MI22-1534 APPLICANT					
MAR 3 1 2	1 00 3	(Use several sheets	if necessary)		Kia Y. Ahn, at al		GRE			
	Ŀ				FILING DATE June 13, 2001		GRO 2814			
*Examiner	Et Of.			U.S. PATENT DOCUMENTS		,	,			
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing If Appro	Dets opriate	
PL	*	2002/0047170	04/02	Cta						
	ΑB	2001/0023120	09/2001	Taunashima et al				<u> </u>		
	AC	2002/0089023	07/2002	Yu et al						
	AD	2002/0175393	11/2002	Baum				<u> </u>	<u> </u>	
	AE	6,495,890	12/2002	One						
	AF	6,444,512	09/2002	Madhukar et al				<u> </u>		
R	AG	6,392,257	05/2002	Ramdani et el				 		
	AH		 					 		
	Al					<u> </u>	<u> </u>	 		
	AJ		!				<u> </u>	<u> </u>		
	AK		<u> </u>				<u> </u>	 		
	AL									
				FOREIGN PATENT DOCUMENT	TS					
		Document Number	Date	Country		Class	Subclass	Yes	No No	
	АМ									
	AN									
	AO	<u> </u>							ــــــ	
 	AP		 			 		₩		
	AQ	<u></u>	<u> </u>			لــــــا				
ļ	,—		IER REFERENC	CE3 (including Author, Title, Date	ı, Pertinent Pages, Etc.))				
	AR									
	AS									
				<u> </u>			-			
	^7									
									-	
EXAMINER				DATE CONSIDER	LED OS	121/0=				
*EXAMINER:	Initial if	if reference considered, wheth py of this form with next com	her or not citation	on is in conformance with MPEP				formance and	not	

OIP	E 3	LIST OF ART CITED	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE OF ART CITED BY APPLICANT Um arvusi dineta il necessary)			ATTY. DOCKET NO. MIZ2-559 AFPLICANT Kis Y. Also, et al			SERIAL NO. 09/881,408		
FEB 19	, ja		,,		FILING DATE			GROUP 2514			
· Emploof	THE SE			U.S. PATENT DOCUMENTS				·			
*Emmines tnited	*Examiner Document Number		Date	Nesso	Neme		Subclass	Filing If Appr	Date opriste		
72	M	6,300,202	10/2001	Hobbs et al							
PZ.	AB	6,525,967	02/2003	Brizer							
12	AC.	4,395,619	05/2002	Soto ot al							
	40										
<u> </u>	AE										
	A.P							ļ			
ļ	AG										
ļ	AH							<u> </u>			
	<i>A</i>										
	"										
	AK										
	. 1							_			
		Document	Deta	FOREIGN PATENT DOCUMEN	75						
		Mamper	Deia	Country		Clase	Subclass	Yes	No No		
	w				ï						
	AN										
	AO AP				-						
	70		•		<u> </u>						
		071	ier referenc	CES (Including Author, Title, Date	, Pertinent Pages, Etc.))					
	AR										
	AS										
				·		•					
	АТ										
examiner				date consider	eD 03/0	4/0	\overline{f} .				
*EXAMINER considered.	i hidal i	f reference considered, whati py of this form with next con	per er not citation provincestion to a	e is to conformance with MPEP policant.	609; Draw line throu	gh eltetion i	fast la ser	faraum sai	pet .		